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Enclosed are the results from the Open Network Systems Interoperability Plugfest performed on:

Module or Cable Assembly Under Test (MUT/CUT):

Vendor and Device Type	GoodOptics QSFP28 SR4 100G Module
Part Number	GOODOPTICS100

Host Under Test (HUT):

Host System 1 Composition	
Network Operating System	SWITCHY-NOS
OS Version	
Bare Metal Switch	Switchy
Part Number	SWITCHY-5000
ONIE Version	2014.08

This testing pertains to the Open Network Systems Interoperability Test Plan, which outlines a series of tests performed on a variety of optical transceivers and cables with bare-metal open switches running Network Operating Systems from multiple vendors. The focus of these tests was basic interoperability which aims to validate the operation of open network systems.

As always, we welcome any comments regarding this Test Suite. If you have any questions about the test procedures or results, please feel free to contact me via e-mail at david@iol.unh.edu or by phone at +1-603-862-0090.

Regards, David Woolf

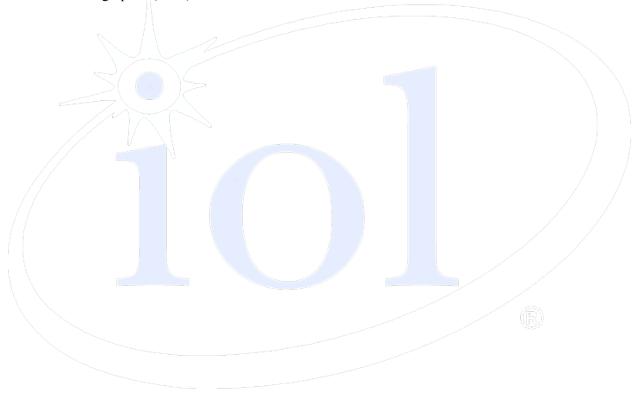
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In section 2, the following equipment was used:

Test System Hardware	
EEPROM Reader	Avago Aport USB-MDIO/TWI Interface Controller

In section 3, the following equipment was used:

Test System Hardware	
Network Analyzer	Agilent E5071C

In section 4, the following equipment was used:

Test System Hardware	
Wide Bandwidth	Agilent DCA-X 86100D
Oscilloscope	
Waveform Analyzer	Agilent 86105C
50GHz Waveform	Agilent DCA-86108B
Analyzer	
Clock Recovery Module	Agilent 83496A
High Performance Serial	Agilent N4903B
BERT	
Signal Quality Analyzer	Anritsu MP1800A with MU181020B 14Gbps PPG* Modules
De-Emphasis Signal	Agilent N4916B
Converter	

^{*}Two modules used during testing

In section 6, an Ixia XM12 was used to generate test traffic:

Test System Hardware		
Ethernet Traffic Generator	Ixia XM12	
Software Version	IxOS 8.10 EA	
Port Types	QSFP28	

The following table contains possible results and their meanings.

Result	Interpretation
PASS	The Device Under Test (DUT) was observed to exhibit conformant behavior.
PASS W/ Comments	The specified behavior is demonstrated by the DUT, however this result indicates that either changes were made to the standard test procedure or results other than the expected results were observed.
FAIL	The DUT was observed to exhibit non-compliant behavior.
INFO	This Test is designed for informational purposes only. While the results may help ensure the interoperability of the DUT, a PASS/FAIL is not given for this test.
WARN	The DUT was observed to exhibit behavior that is not recommended.
N/A	Not Applicable. This test is not applicable for the DUT.
N/S	Not Supported. This test was not run due to features not implemented on the DUT.
N/T	Not tested. This test was not run.

Summary of Results- Conformance	
Test	Result
Test 1.1: ONIE Compliance Environment	N/A
Test 1.2: Installing and uninstalling a NOS through ONIE via HTTP server	PASS
Test 4.1.1: Calibration for 100G QSFP28 Module and AOC Testing	PASS
Test 4.1.2: 100G QSFP28 Golden Module Verification	PASS
Test 4.2.1: Transmitter Eye Mask for 100G QSFP28 (Modules Only)	PASS
Test 4.2.2: Output Eye Mask for 100G QSFP28	PASS
Test 5.1.1: Output Rise and Fall Times for 100G Host	PASS
Test 5.1.2: Transmitter Eye Mask for 100G Host	PASS
Test 5.1.3: Total Jitter for 100G Host	PASS
Test 5.1.4: Input and Output Return Loss on 100G Host	PASS

Summary of Results - Interoperability		
Test	Result	
Test 2.1: Physical Compatibility with Supporting Devices	PASS	
Test 2.2: Host Management of Module or Cable Assembly	PASS	
Test 2.3: Diagnostic Optical Monitor Support	PASS	
Test 6.1: Establish Baseline Performance Analysis	PASS	
Test 6.2: Link Detection on Power Up	PASS	
Test 6.3:Packet Error Rate Estimation	PASS	
Test 6.4: Packet Loss/Stress Test	PASS	

Notes	

Conformance Test Results	
Test Information	Test Result
Test 1.1: ONIE Compliance Environment	
<i>Purpose</i> : To verify that a host can pass a random sampling of ONIE Compliance Environment tests.	N/A
Comments on Test Procedure	
The random sampling of tests from the ONIE Compliance Environment was not used. Comments on Test Results	
Additional Comments	
This test is only applicable to Hosts which have not performed ONIE comp previously.	cliance testing

Test Information	Test Result
Test 1.2: Installing and uninstalling a NOS through ONIE via HTTP server Purpose: To verify that a NOS can be successfully installed through ONIE.	PASS
Comments on Test Procedure	
This test was completed using the standard procedure as written in the Test Plan. The rand from the ONIE Compliance Environment was not used.	om sampling of tests
Comments on Test Results	
Part A: The DUT was able to install the NOS via ONIE. Part B: The DUT was able to uninstall the NOS via ONIE.	
Additional Comments	

Test Information	Test Result
Test 4.1.1: Calibration for 100G QSFP28 Module and AOC Testing Purpose: To establish Electrical input baseline of the SFP+ optical modules.	PASS
Comments on Test Procedure	
This test was completed using the standard procedure.	
Comments on Test Results	
The signal at point TP1 was calibrated to meet SFF-8431 requirements for Mo	odule Electrical Input Signals.
Additional Comments	

Test Information	Test Result
Test 4.1.2: 100G QSFP28 Golden Module Verification	
Purpose: To record the optical output eye mask margin of the Golden Optical Unit. This unit will be used to test SFP+ Modules at TP4.	PASS
Comments on Test Procedure	
This test was completed using the standard procedure.	
Comments on Test Results	
Using the input signal calibrated during 4.1.1, a Golden Module was selected that was co 2012 for a 10G signal at TP2.	mpliant to IEEE Std. 802.3-
Additional Comments	

Test Information	Test Result
Test 4.2.1: Transmitter Eye Mask for 100G QSFP28	
Purpose: To verify that the device (Module or Cable Assembly) under test (DUT) demonstrates electrical output characteristics that meets the specified requirements.	PASS
Comments on Test Procedure	
This test was completed using the standard procedure.	
Comments on Test Results	
The hit ratio did not exceed 5 x 10 ⁻⁵ . The Mask Margin was greater than 0.	
Additional Comments	The state of the s

Test Information	Test Result
Test 4.2.2: Output eye mask for 100G QSFP28	PASS
Purpose: To verify that the device (Module or Cable Assembly) under test (DUT) demonstrates electrical output characteristics that meets the specified requirements.	TASS
Comments on Test Procedure	
This test was completed using the standard procedure.	
Comments on Test Results	
The hit ratio did not exceed 5 x 10^{-5} . The Mask Margin was greater than 0.	
Additional Comments	

Test Information	Test Result
Test 5.1.1: Output Rise and Fall Times for 100G Host	
Purpose: To verify that the Eye Mask Hit Ratio is within the conformance limits.	PASS
Comments on Test Procedure	
The test was completed with the standard procedure.	
Comments on Test Results	
The device under test exhibited the expected behavior.	
Additional Comments	The state of the s

Test Information	Test Result
Test 5.1.2: Transmitter Eye Mask on 100G Host	D. CC
Purpose: To verify that the Eye Mask Hit Ratio is within the conformance limits.	PASS
Comments on Test Procedure	
The test was completed with the standard procedure.	
Comments on Test Results	
The device under test exhibited the expected behavior.	
Additional Comments	

Test Information	Test Result
Test 5.1.3: Total Jitter for 100G Host	
Purpose: To verify that the Total Jitter (TJ) is within the conformance limit.	PASS
Comments on Test Procedure	
The test was completed with the standard procedure.	
Comments on Test Results	
The device under test exhibited the expected behavior.	
Additional Comments	

Test Information	Test Result
Test 5.1.4: Input and Output Return Loss on 100G Host	/ /
Purpose: To verify that the differential input and output return loss of the DUT is within conformance limits.	PASS
Comments on Test Procedure	
The test was completed with the standard procedure.	®
Comments on Test Results	
The device under test exhibited the expected behavior.	
Additional Comments	
See Appendix B	

Interoperability Test Results	
Test Information	Test Result
Test 2.1: Physical Compatibility with Supporting Devices	
<i>Purpose</i> : To verify that the mechanical form factor is compatible with devices for interoperability purposes.	PASS
Comments on Test Procedure	1
Comments on Test Results	
Comments on Test Results Part A: The MUT/CUT was able to be inserted into the Host. Part B: This test is not applicable to Cable Assemblies.	
Part C: The MUT/CUT was able to be removed from the Host.	
Additional Comments	

Test Information	Test Result
Test 2.2: Host Management of Module or Cable Assembly Purpose: To verify that the MUT/CUT is manageable via the Host complex.	PASS
Comments on Test Procedure	
The test was completed with the standard procedure.	
The lost was completed with the standard procedure.	
Comments on Test Results	
Comments on Test Results Part B: The EEPROM data of the MUT/CUT was readable. The serial numb	

Test Information	Test Result
Test 2.3: Diagnostic Optical Monitor Support	1 est Result
Purpose: To verify that the MUT/CUT (active optical cable only) supports diagnostic functions via the Host complex.	PASS
Comments on Test Procedure	
The test was completed with the standard procedure.	
Comments on Test Results	
Part A: The MUT/CUT supports diagnostic monitoring and the diagnostic information freedable by the NOS.	om the EEPROM was
Additional Comments	and the second s
	®

Test Information	Test Result
Test 6.1: Establish Baseline Performance Analysis	PASS
Purpose: To establish a baseline performance analysis of the HUT.	FASS

Comments on Test Procedure

This test was completed using a modified procedure. Because of a lack of 40G Golden Modules, the Host was baselined using each 40G MUT/CUT.

Comments on Test Results

The baseline performance of the Host was determined to be 90% line rate. All proceeding tests in Group 6 were conducted using this line rate.

Additional Comments

Test Information	Test Result
Test 6.2: Detection on Power Up	
Purpose: To determine if the MUT/CUT, HUT and LP establish a link while varying the power up sequence.	PASS

Comments on Test Procedure

This test was completed using the standard procedure.

Comments on Test Results

- **Part A:** The Host and Link Partner were able to establish a valid link with this MUT/CUT while fully powered and operational.
- **Part B:** The Host and Link Partner were able to establish a valid link with this MUT/CUT when the Link Partner was powered on after the Host.
- **Part C:** The Host and Link Partner were able to establish a valid link with this MUT/CUT when the Host was powered on after the Link Partner.

Additional Comments

Test Information	Test Result
Test 6.3:Packet Error Rate Estimation	
<i>Purpose</i> : To determine if a Host can exchange packets with a Module or Cable Assembly such that a bit error rate of 10^{-12} is achieved	PASS
Comments on Test Procedure	
This test was completed using the standard procedure. Comments on Test Results	
Part A: All 247,000,000 frames transmitted by TS1 were received by TS2. Part B: All 10,506,539,320 frames transmitted by TS1 were received by TS2. Additional Comments	

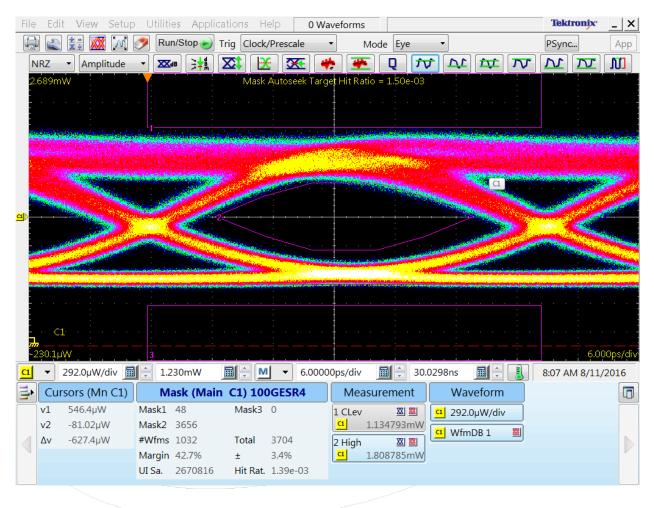
PASS Packet Loss/Stress Test Parpose: To verify that no obvious buffer management problems occur when directing a rege volume of traffic at the Host and Module/Cable Assembly combination. Comments on Test Procedure In this test was completed using the standard procedure. Comments on Test Results Parts A-D: All 1,000,000,000 64-byte frames transmitted by TS1 were received by TS2. All 1,000,000,000 1518-byte frames transmitted by TS1 were received by TS2. All 1,000,000,000 1518-byte frames transmitted by TS1 were received by TS2.	Test Information				Test Result
his test was completed using the standard procedure. comments on Test Results arts A-D: All 1,000,000,000 64-byte frames transmitted by TS1 were received by TS2. All 1,000,000,000 1518-byte frames transmitted by TS1 were received by TS2.	Purpose: To verify tha	t no obvious buffer			ng a PASS
omments on Test Results arts A-D: All 1,000,000,000 64-byte frames transmitted by TS1 were received by TS2. All 1,000,000,000 1518-byte frames transmitted by TS1 were received by TS2.	Comments on Test Pi	rocedure			
Arts A-D: All 1,000,000,000 64-byte frames transmitted by TS1 were received by TS2. All 1,000,000,000 1518-byte frames transmitted by TS1 were received by TS2.	This test was complete	d using the standard	d procedure.		
All 1,000,000,000 1518-byte frames transmitted by TS1 were received by TS2.	Comments on Test Ro	esults		and the second s	
dditional Comments					
	Additional Comments	s			

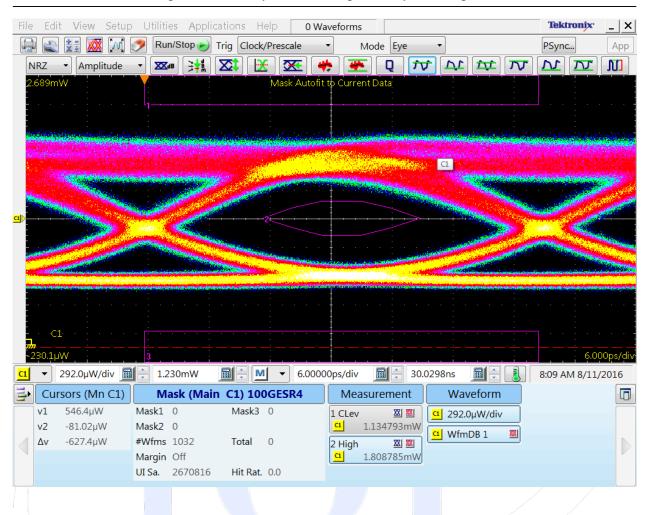
Appendix A: EEPROM Data

```
GOODOPTICS CORP QSFP28 module
Part Number: GOODOPTICS100 Serial Number: CU2003T
GOODOPTICS_CU2003T____EEPROMdecode_20160802155646.txt
SERIAL ID Keys:
BR NOMINAL: 25750
CONNECTOR: 12
CU ATTENUATE 2 5: 0
CU ATTENUATE 5 0: 0
DEVICE TECH: 0x0
ENCODING: 5
EXTENDED MODULE: 0x0
EXT IDENTIFIER: 204
EXT RATE COMPLY: 0
IDENTIFIER: 17
LENGTH OM1 62 5UM: 0
LENGTH OM2 50UM: 0
LENGTH OM3 50UM: 70
LENGTH OM4 OR CU: 100
LENGTH SMF KM: 0
MAX CASE TEMP: 0
SPEC COMPLIANCE: 0x80 0x0 0x0 0x0 0x0 0x0 0x0 0x0
VENDOR NAME: GOODOPTICS CORP
VENDOR OUI: 0x0 0x90 0x65
VENDOR PN: GOODOPTICS100
VENDOR REV: A0
WAVELENGTH: 850.0
WAVELEN TOLERANCE: 10.0
0 \times 0 \quad 0 \times 
0x0 0x0
I2C Address A0h, bytes 0-127, in hex
0000x: 1107020f 000f0000 00555555 55000000
0010x: 00000000 0000111e 00008116 00000000
0020x: 00000015 00170028 0034000c 00000007
0030x: 00001d57 19ae125e 19bd0000 00000000
0040x: 00000000 00000000 00000000 00000000
0050x: 00000000 00000001 cc000000 00000000
0060x: 0000ff00 00000000 00000000 00000000
0070x: 00000000 00000000 00000000 00000000
I2C Address A0h, page 0, bytes 128-255, in hex
0000x: 11cc0c80 00000000 00000005 ff000023
0010x: 00003200 46494e49 53415220 434f5250
0020x: 20202020 00009065 46544c43 39353531
0030x: 5245504d 20202020 41304268 07d0003a
0040x: 0207ffde 43553230 30335420 20202020
```

0050x: 20202020 31353037 31312020 0c1067a9 0060x: 00000000 00000000 00000000 0070x: 00000000 00000000 00000000

Appendix B: Pluggable Module / Cable Electrical Data





Appendix C: Host Electrical Data

